



1/25/2008

RELIABILITY MONITOR REPORT  
FOR

**SAT 1.2 $\mu$ m Silicon Gate CMOS**

**MAXIM Integrated Products**

120 San Gabriel Dr.  
Sunnyvale, CA 94086

This Report was prepared by  
Maxim Reliability Engineering

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1987ETM+

The calculated failure rate for devices using this process is:

**FAILURE RATE:                    MTTF (YRS): 9108                    FITS: 12.5**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%                    Ea: 0.7                    Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

---

**Process Information:**

Process Description:            SAT 1.2µm Silicon Gate CMOS

---

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0549	MAX1987ETM+	135C, 5.25V	1000 HRS	47	0	
				<b>Total:</b>		<b>0</b>	

**FAILURE RATE:                    MTTF (YRS): 9108                    FITS: 12.5**